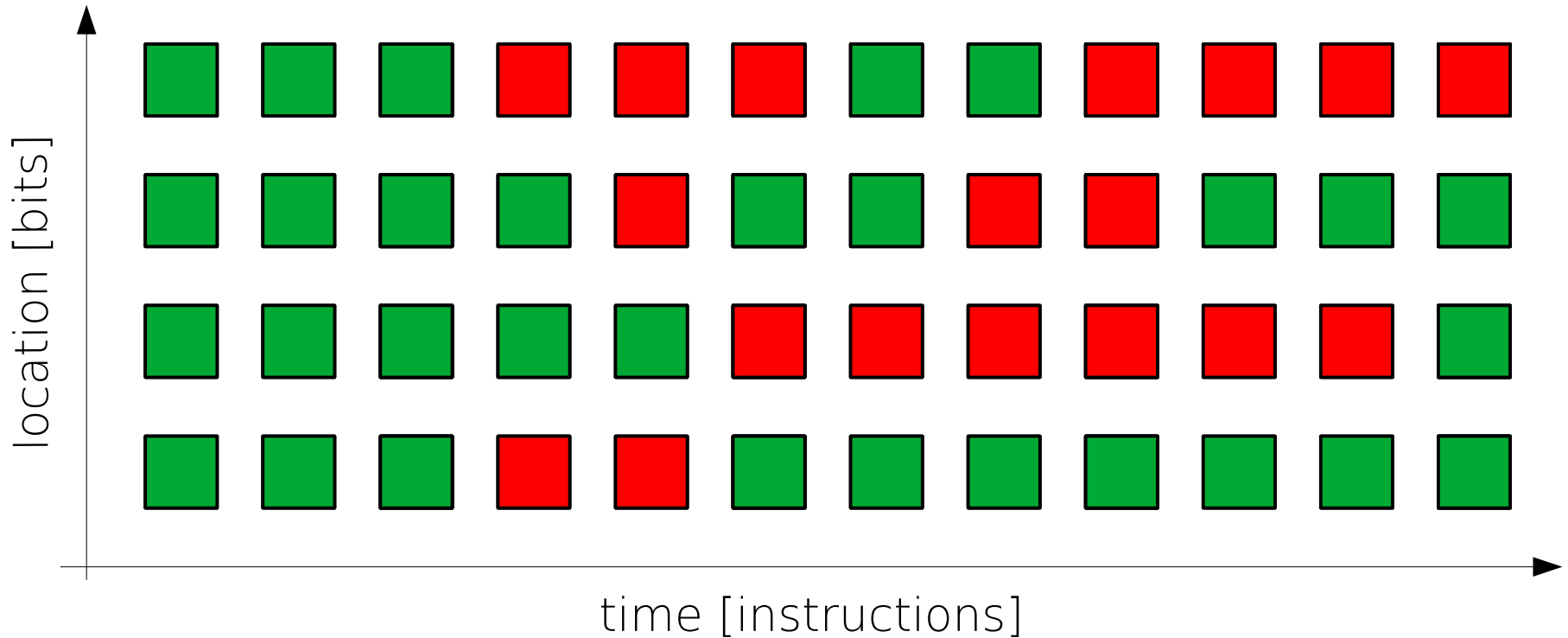


# Program-Structure-Guided Approximation of Large Fault Spaces

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- Devices with high responsibility need to be reliable
- Shrinking transistors make hardware more vulnerable
- Quantifying software safeness in presence of transient hardware errors: Simulation-based fault injection
- Problem: Fault injection campaign run time



Fault

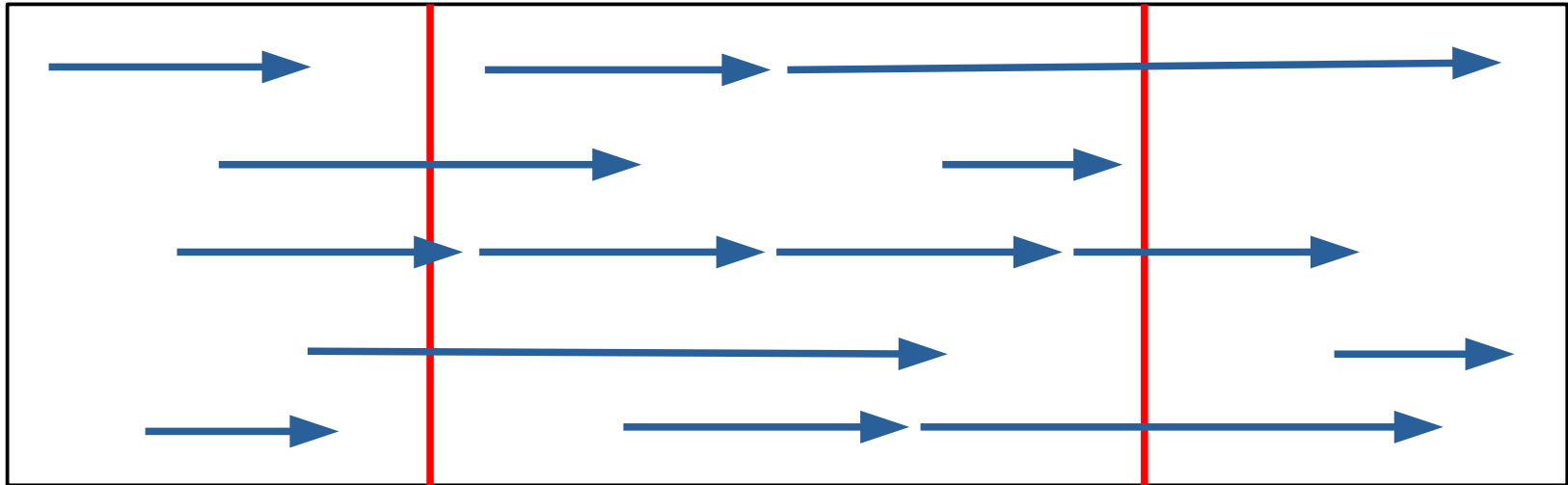


Expected Behavior




Unexpected Behavior

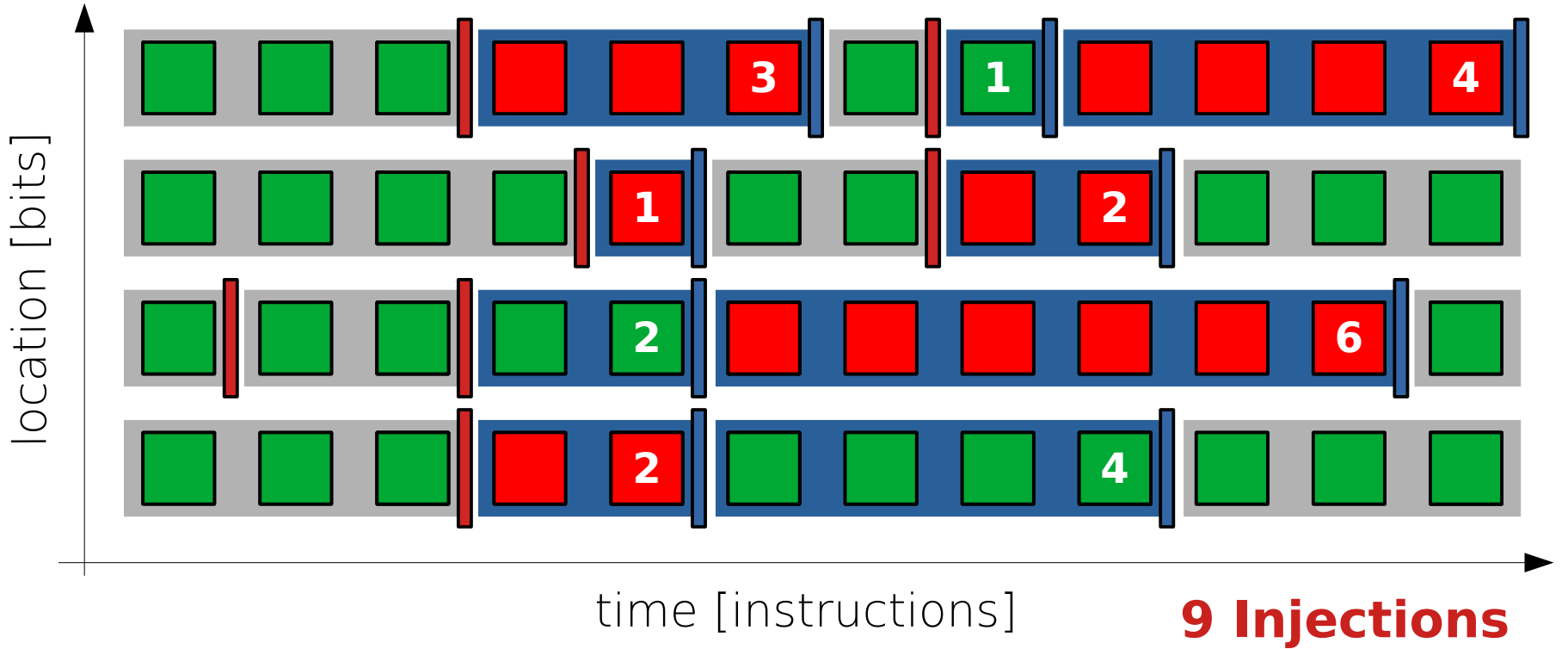
# Approach in a nutshell

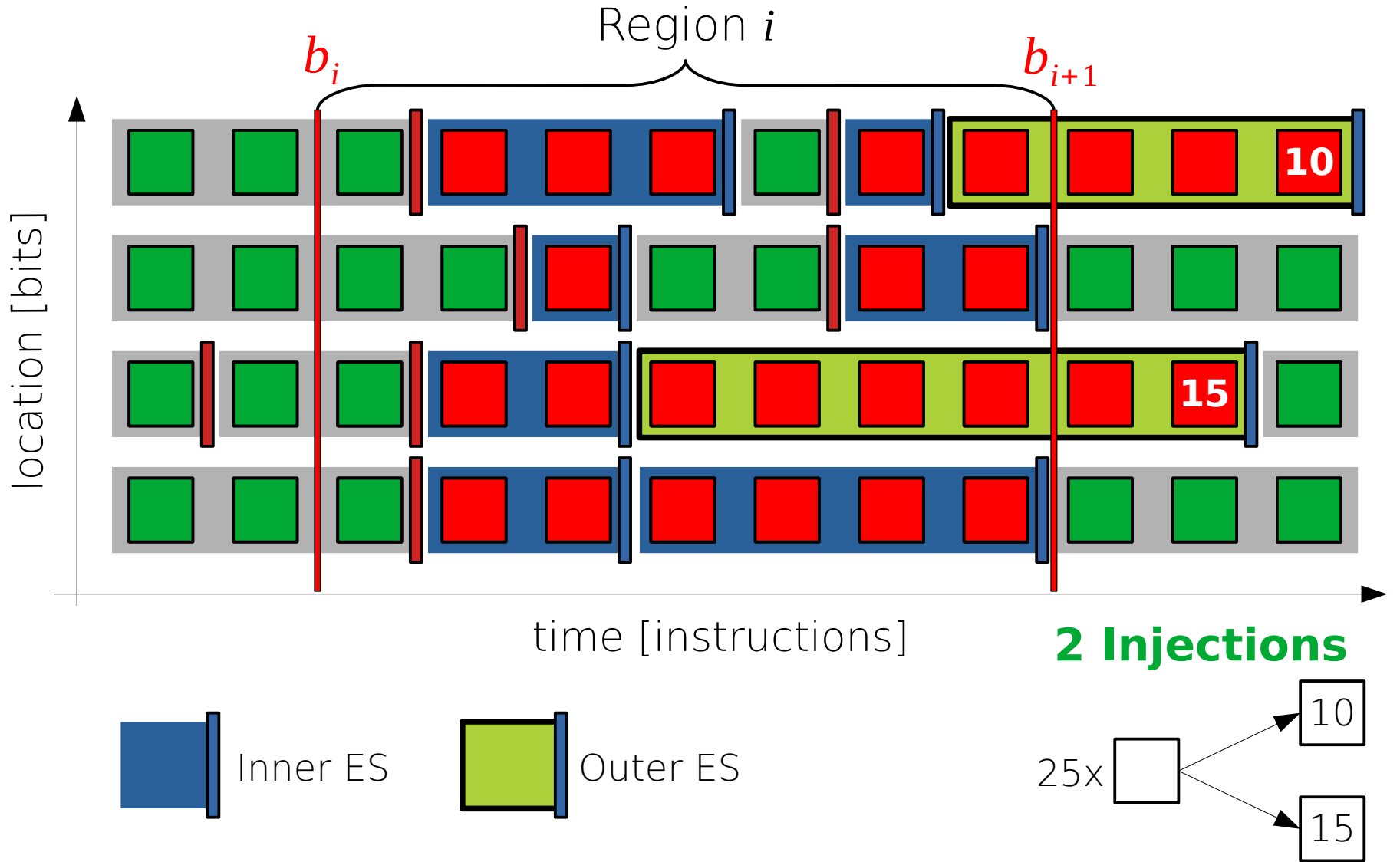


 Dataflow

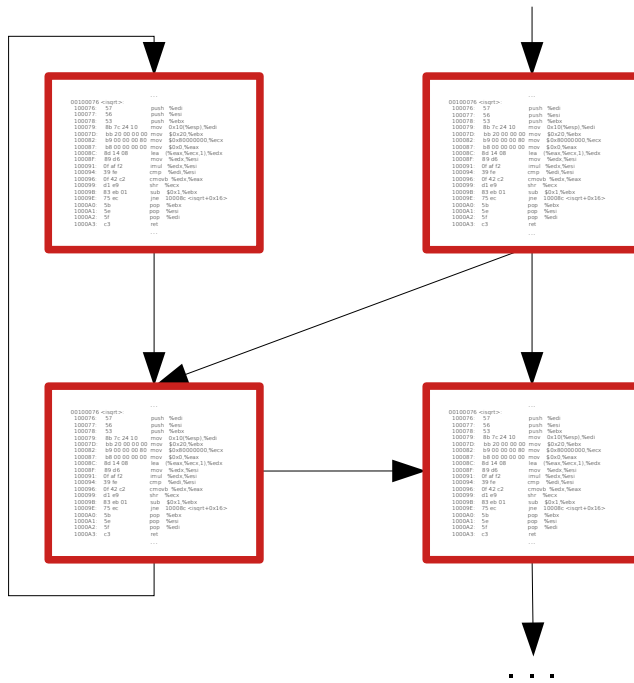
 Ignored  
Dataflow

## Def/Use-Pruning

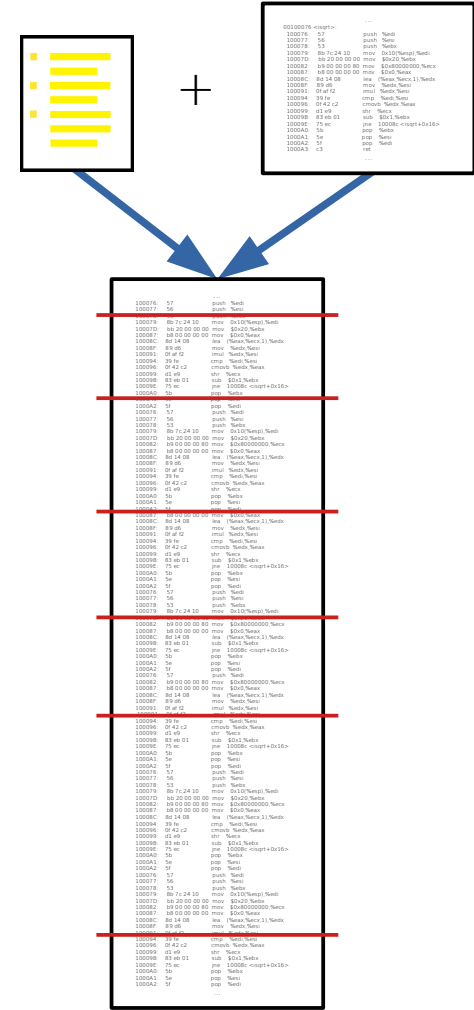




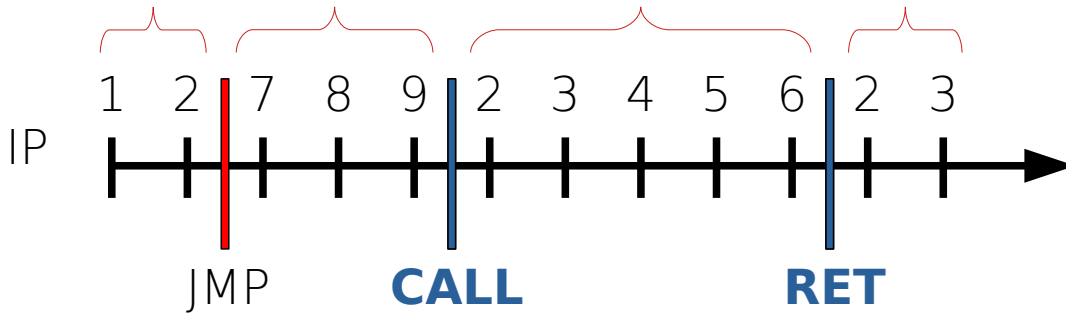
## Static Basic Blocks



trace + objdump



## Dynamic Basic Blocks



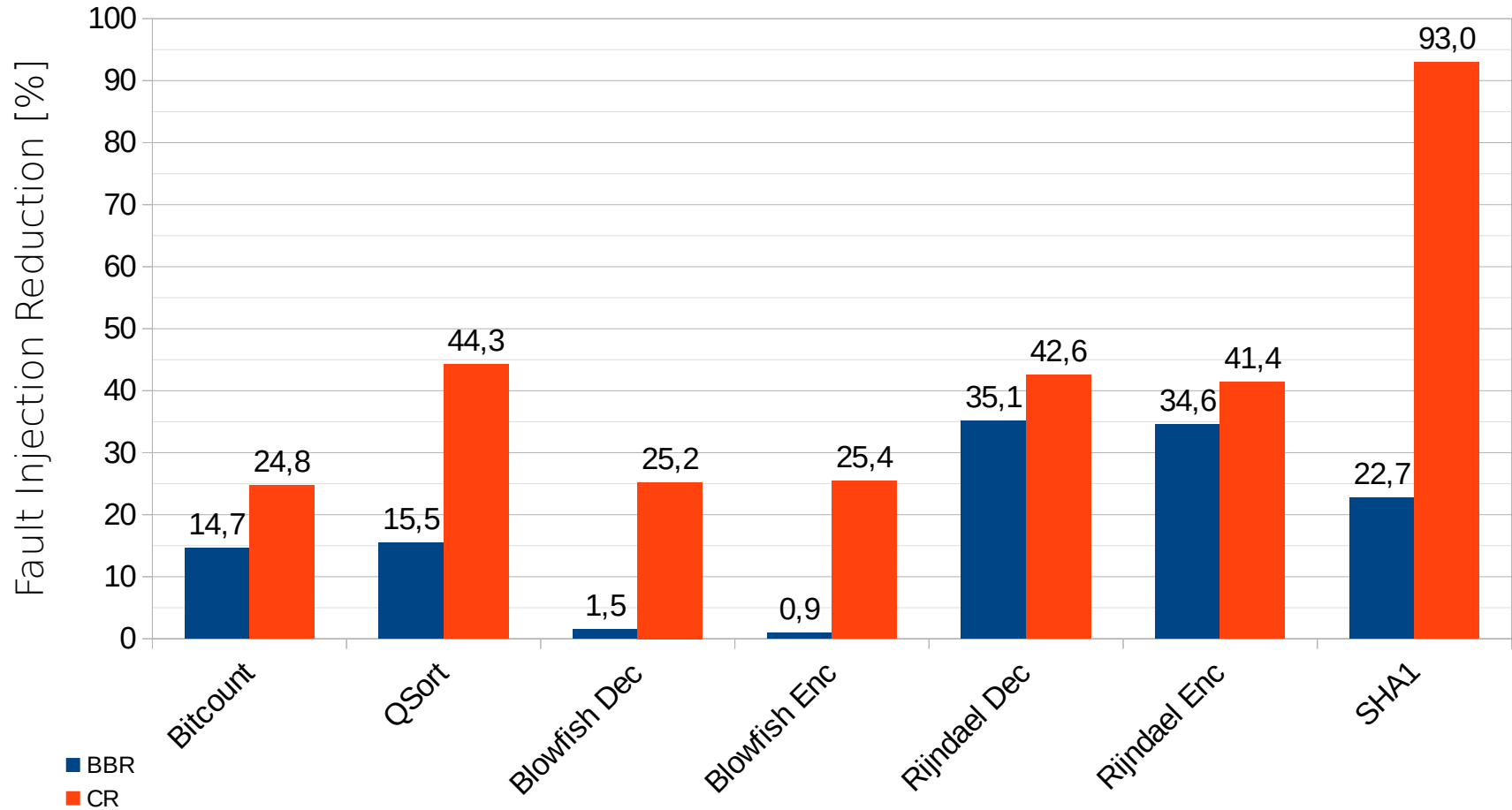
- Fault injection framework **FAIL\*** is extended and emulates on the IA-32 simulator Bochs
- Used hardware:
  - Def/Use + FSR calculation: Intel i5-7400 @ 3Ghz (4 cores)
  - FI Campaign: 17 Intel Xeon @ 2.67 Ghz (12 cores each)
- Dimensions of the evaluation
  - Seven selected Programs of the automotive and security branch of the MiBench benchmark suite
  - Two instantiations of the FSRs: basic block and call regions
  - Three fault models: memory, GP registers, combined



- Number of injections after the precise and complete Def/Use pruning is the baseline
- FSR calculation took end-to-end no more than 4.1 seconds

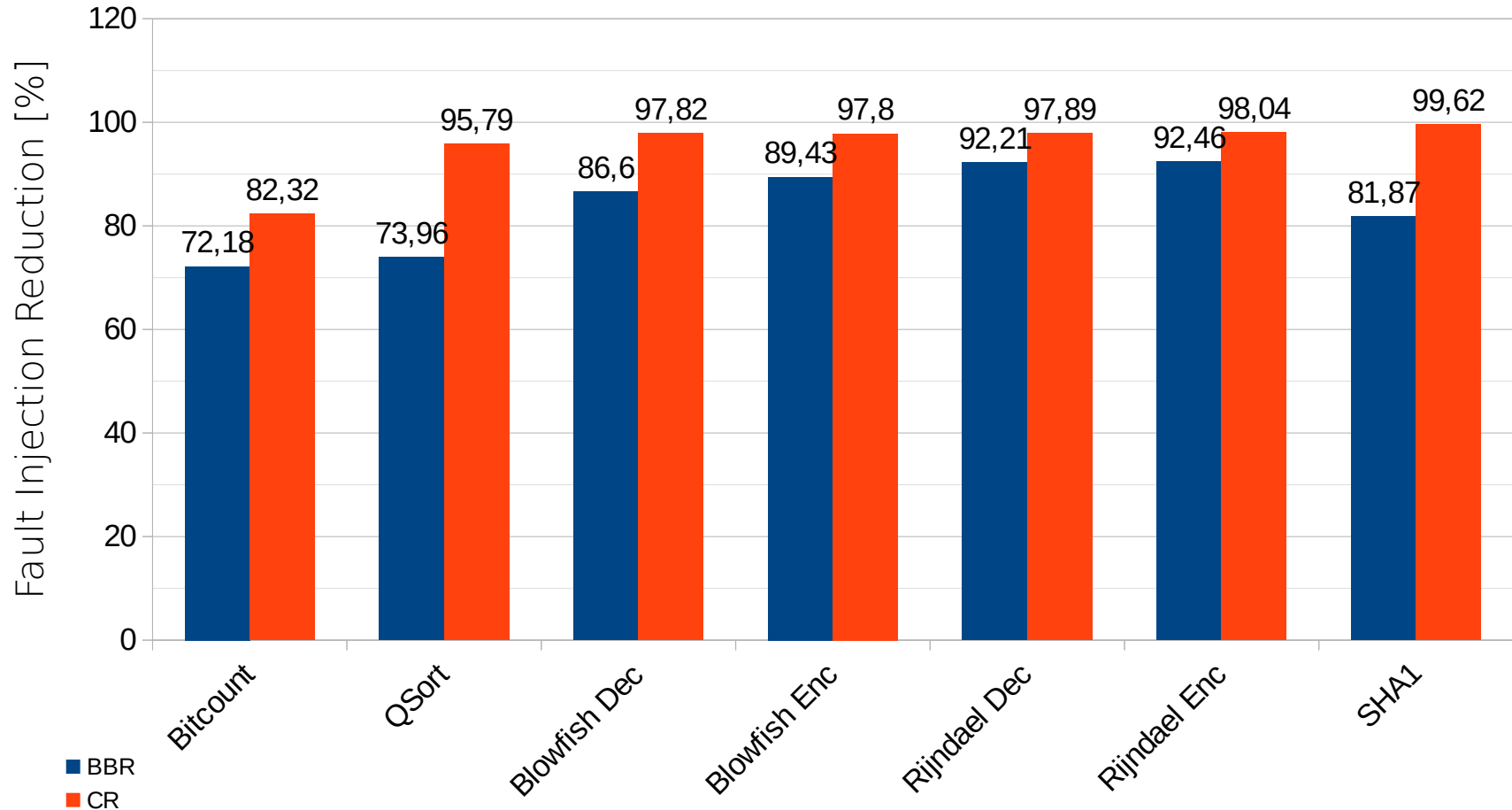
fault model		Memory	Register	Combined
#injections	BBR[%]	-9.79	-83.73	-69.91
	CR [%]	-38.03	-95.44	-83.87

## Memory Fault Space



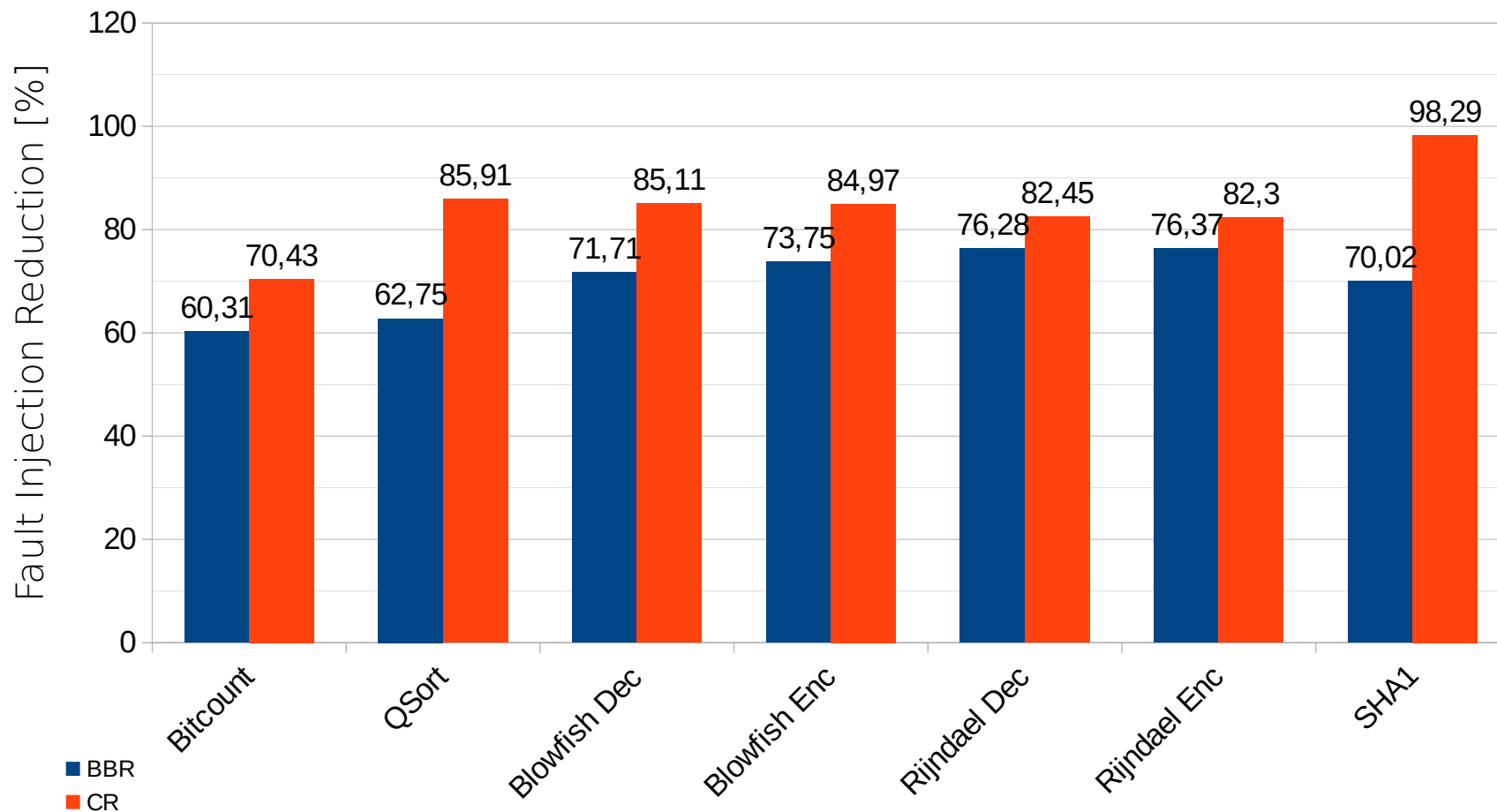
**Deviation for BBR below 0.2%**

## Register Fault Space



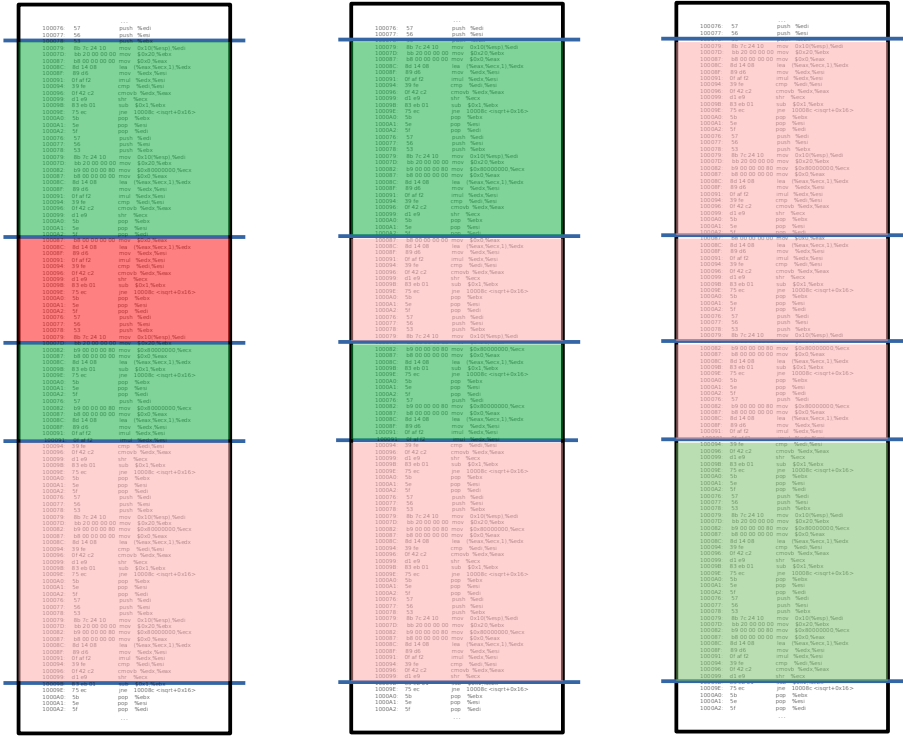
**High Reduction → High Deviation**  
**BBR up to 41.3 %, CR up to 108.8 %**

## Combined Fault Space



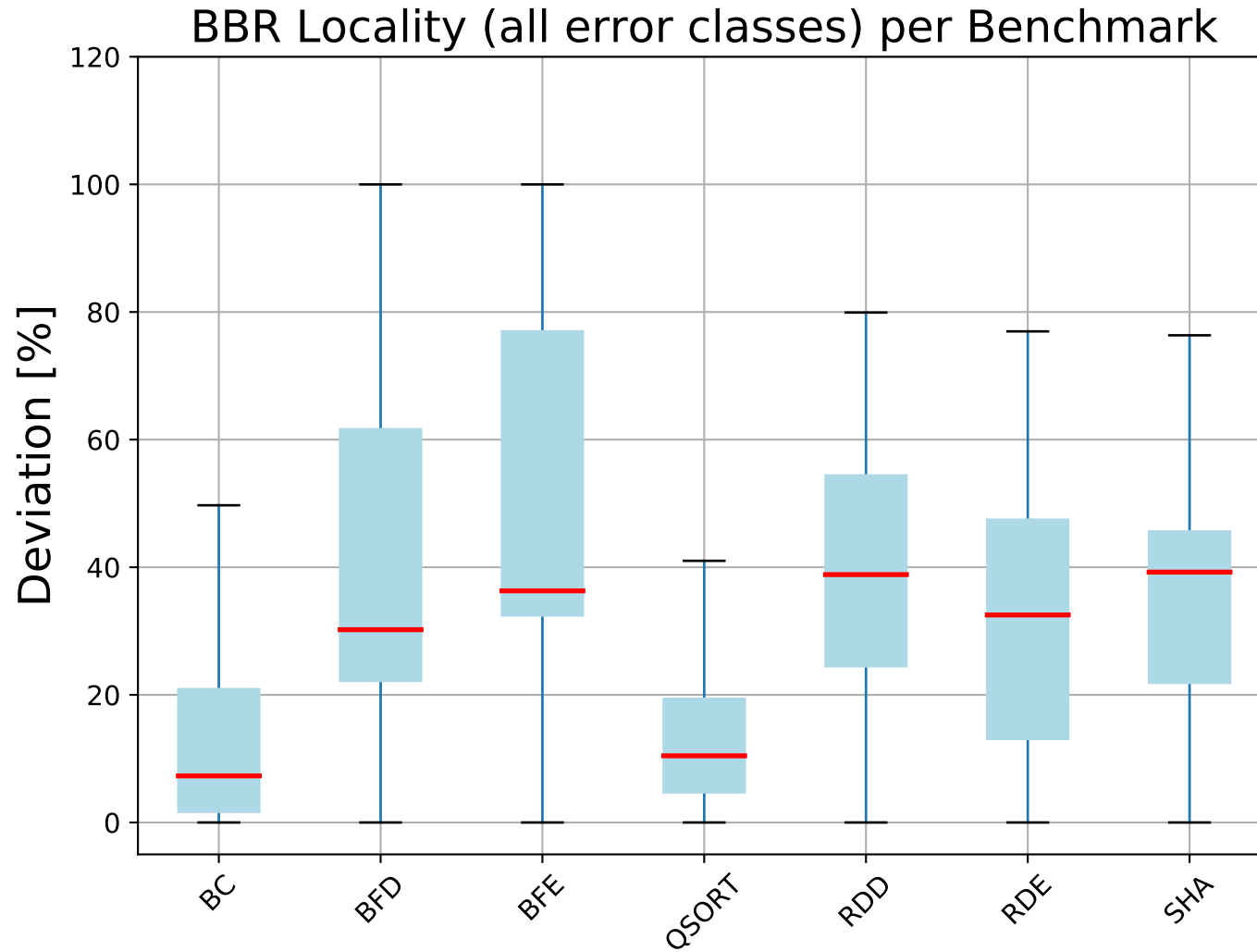
**Deviation BBR 0.2% - 2.7%**

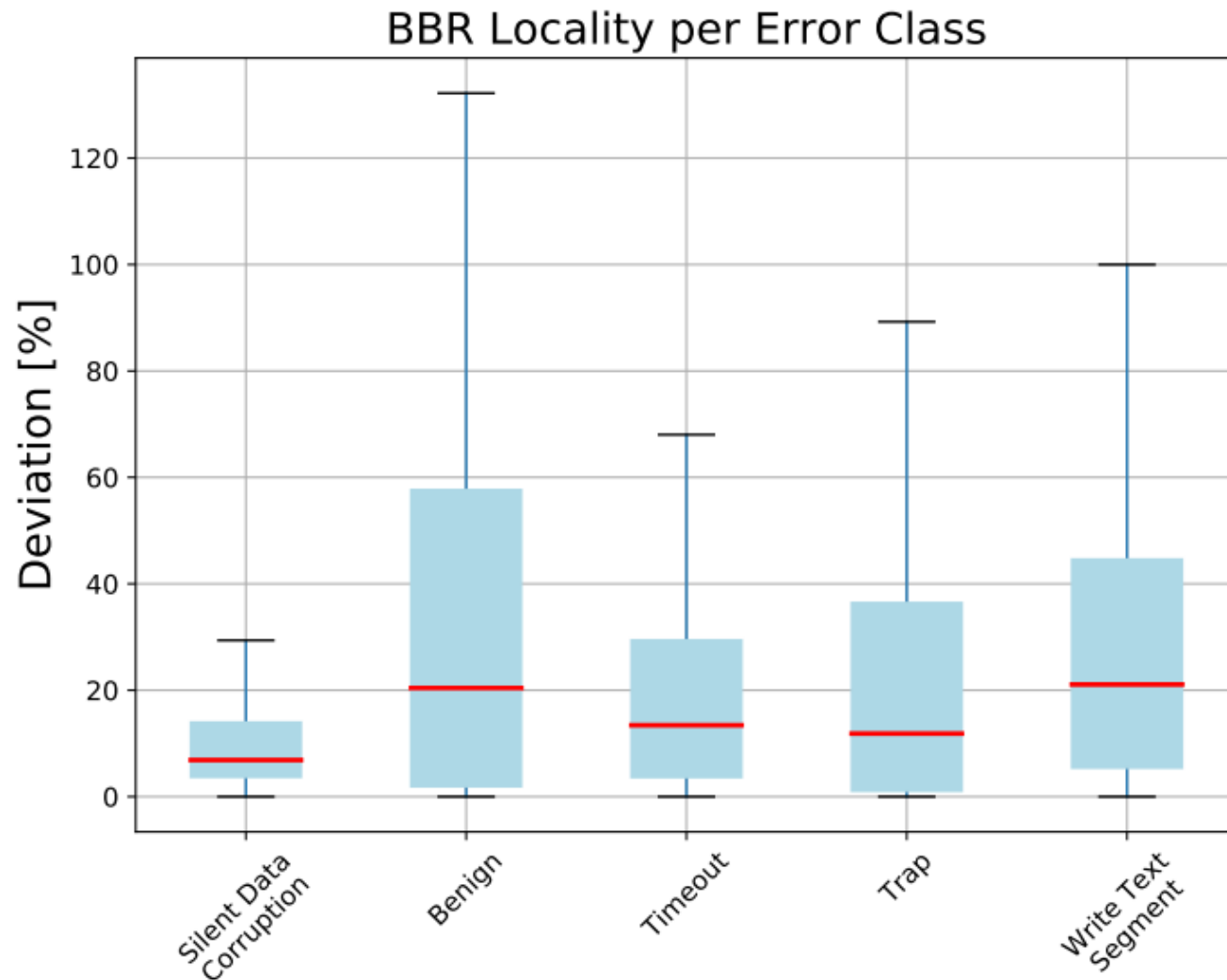
More Benign  ↔  ↔  ↔  More Errors

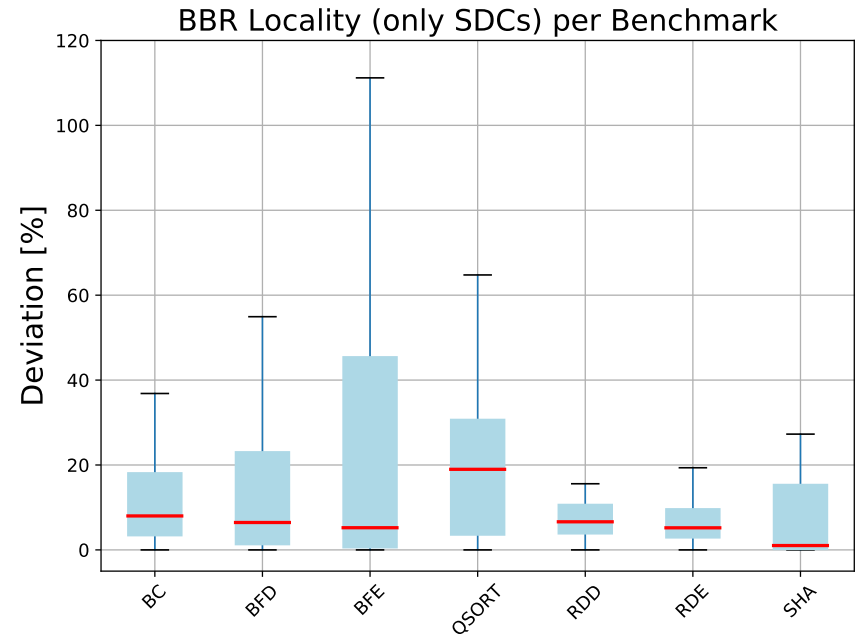
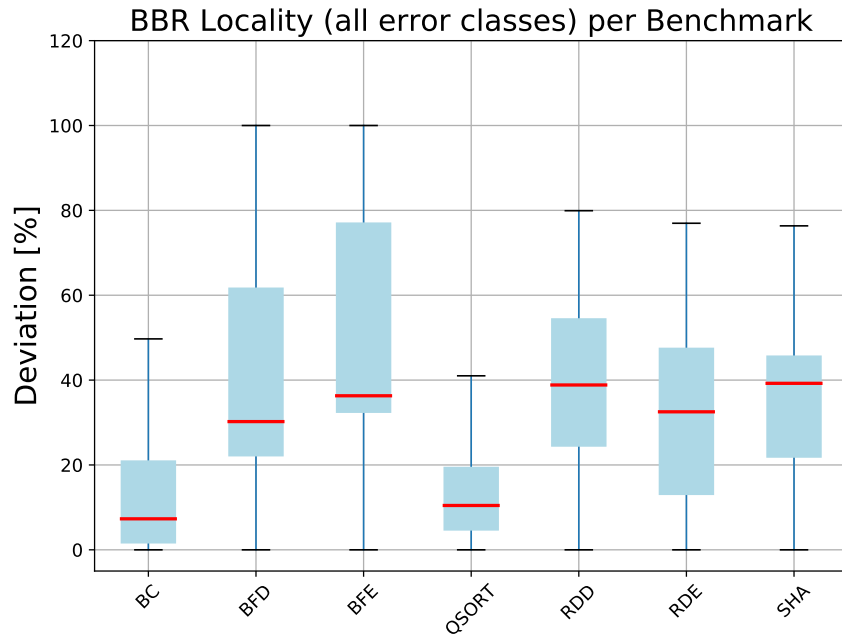


- Dimensions of the evaluation
  - The seven programs from MiBench
  - For every error class: Silent Data Corruption, Benign, Timeout, Trap, Write Text Segment
  
- Comparison of two error-rate vectors
  - Precise vector from Def/Use
  - Approximated one from BBRs
  - Geometric mean over the class deviations

Baseline                      Good Locality                      Bad Locality







**BBRs keep locality of the results for SDCs in combined FM**

**Memory fault space: Median 0%, 75-quantile mostly 0%**

Register fault space: As expected, bad locality of the results



- What we did
  - We extract the program structure from a program trace
  - The extracted structure leads to fault space regions
  - Dataflows which cross regions borders will be injected
- We could reduce the number of required faults
  - Combined fault space -76% with 2.7% deviation
  - Even more precise for the memory fault space
  - Locality of the results kept regarding silent data corruption
- Check it out: **FAIL\*** - Fault Injection Leveraged (<https://github.com/danceos/fail>)

